

Notice of References Cited	Application/Control No. 10/063,214	Applicant(s)/Patent Under Reexamination LEHNER ET AL.	
	Examiner Jason Proctor	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,796,985	08-1998	O'Brien et al.	716/6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Adel S. Sedra and Kenneth C. Smith, "Microelectronic Circuits", 1987, Holt Rinehart and Winston Inc., 2nd Edition, pages 350-355
	V	Pinhong Chen, Desmond A. Kirkpatrick, Kurt Keutzer, "Miller factor for gate-level coupling delay calculation"; 2000; ACM; pages 68-74
	W	Francky Leyn, Walter Daems, Georges Gielen, Willy Sansen, "A Behavioral Signal Path Modeling Methodology for Qualitative Insight in and Efficient Sizing of CMOS Opamps"; 1997; IEEE; pages 374-381
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.